

Search Notes

Application/Control No.

10/655,942

Examiner

Paul D. Kim

Applicant(s)/Patent under
Reexamination

HASEGAWA, NAOYA

Art Unit

3729

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---------------------------------------|-----------|----------|
| 29 | 603.07 603.08 603.11- 603.16 | 2/22/2006 | PK |
| | 603.18 | | |
| 360 | 324.11 | | |
| | 324.12 | | |
| | 324.2 | | |
| 216 | 22,39 40 | | |
| 427 | 127 128 | | |
| 451 | 5, 41 | | |
| 360 | 121 122 | | |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|-----------|------|
| Reviewed Parent Application 09/905,330 (US PAT. 6,751,073) | 2/22/2006 | PK |
| Text Search EAT/NPL (IEEE) | 2/23/2006 | PK |
| Updated Text Search EAST | | |
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